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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM 10008408	FILING DATE 11/13/2001	CLASS 714	SUBCLASS 738	GAU 2133	EXAMINER KERLERO S
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**APPLICANTS: Purtell Michael; Yamoto Hiroaki;
RSD

**CONTINUING DATA VERIFIED: NONE
JC 4/2/04

** FOREIGN APPLICATIONS VERIFIED: NONE
JC 4/2/04

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☐ yes ☒ no

35 USC 119 conditions met

☐ yes ☒ no

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

ADTST.037AUS

TITLE : Event based test system having improved semiconductor characterization map

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims
			Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> TERMINAL		Application Examiner	
DISCLAIMER		PREPARED FOR ISSUE	
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